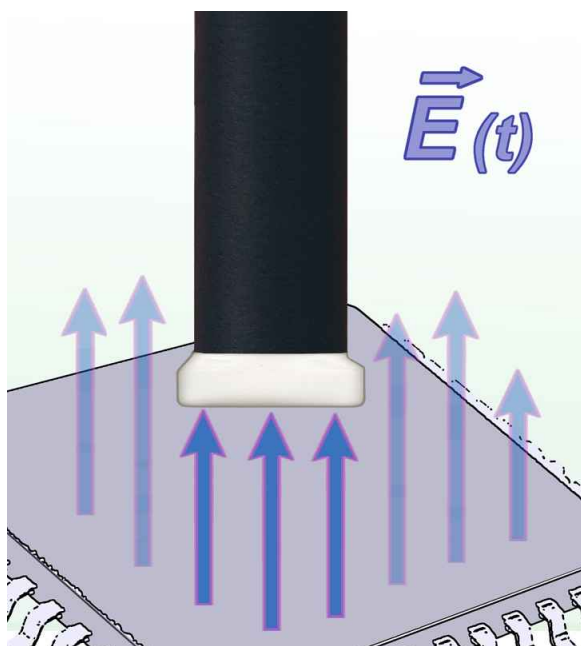


RF-E 03

E-Field Probe 30 MHz up to 3 GHz

LANGER
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Short description

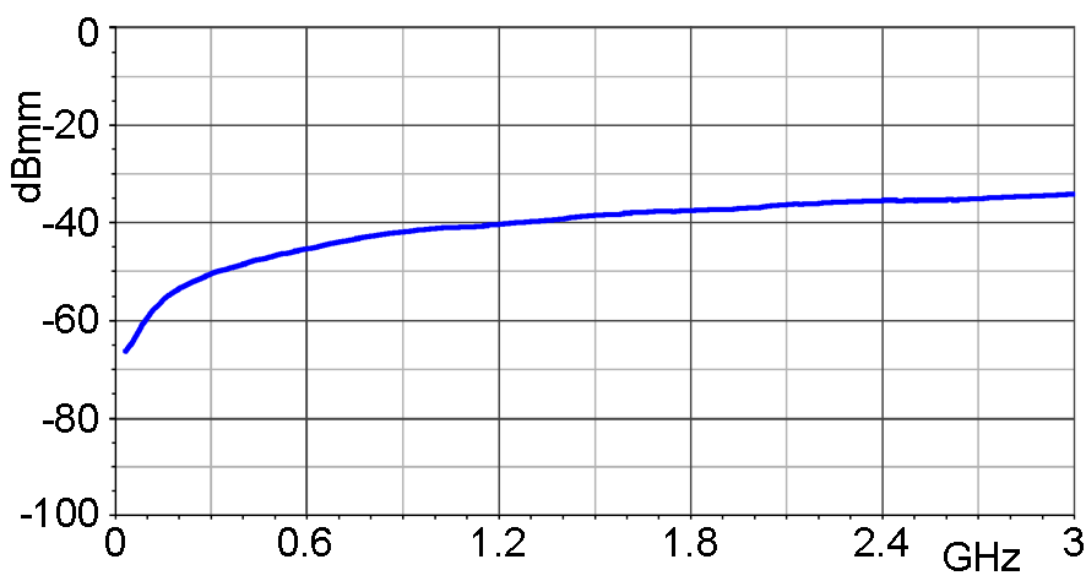
The electrode underneath the RF-E 03 probe head is approx. 4 x 4 mm. With it small E field sources can be localized, e.g. conducting paths, single component of Printed circuit boards. The RF-E 03 probe was developed for Langer scanner.

The RF-E 03 is a passive near field probe. Normally the probe head is positioned directly on the measured object (high electrical field strength). The near field probe is small and handy. It has a sheath current attenuation and is electrically shielded. It can be connected to a spectrum analyzer or an oscilloscope with a 50 Ω input. The E field probe has an internal terminating resistance.

Technical parameters

Frequency range	30 MHz - 3 GHz
Connector - output	SMB, male, jack
Electrode surface area	$\approx (4 \times 4)$ mm

Frequency response

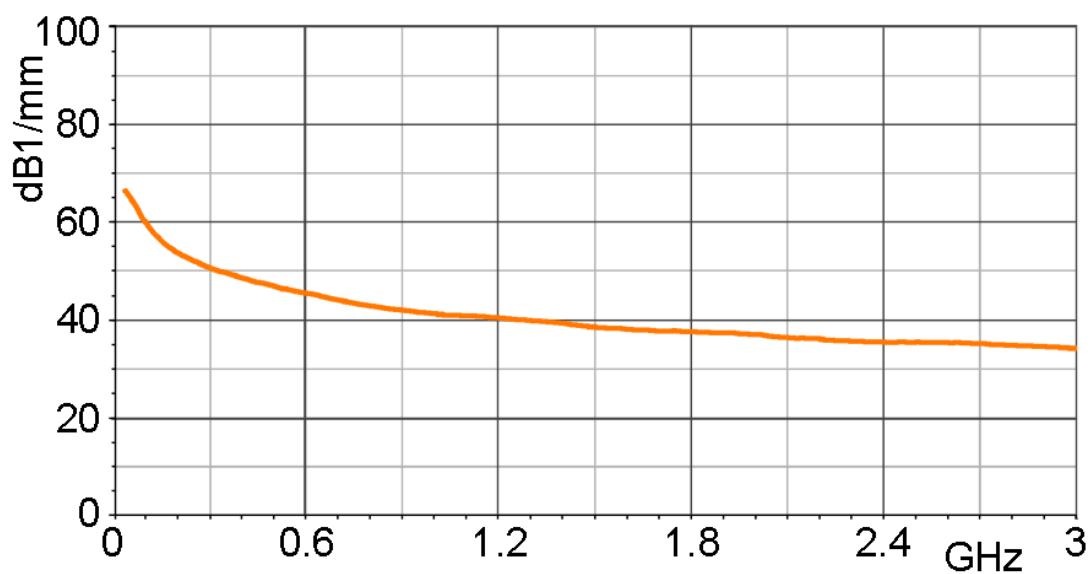


RF-E 03

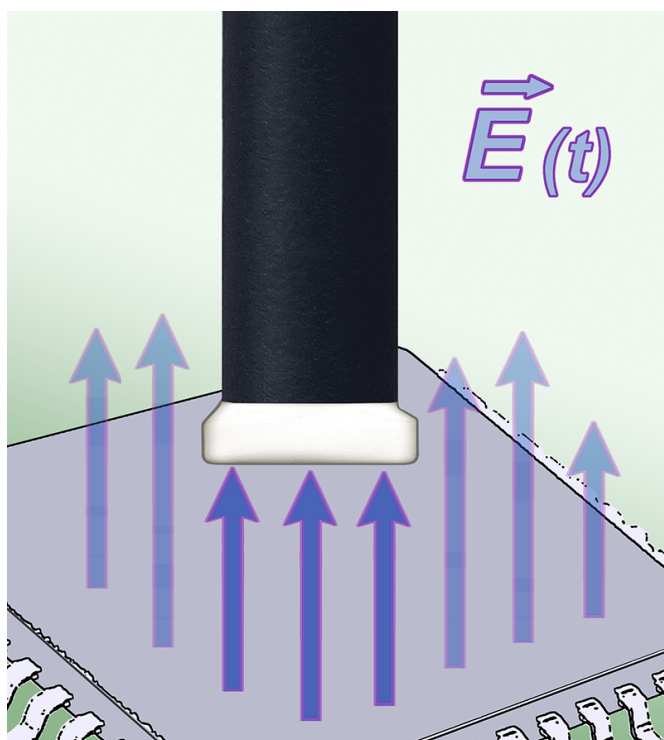
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E- field correction curve [dB μ V/mm] / [dB μ V]



Measuring principles



RF-E 03

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Probe head



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